

Notice of References Cited	Application/Control No. 10/713,808	Applicant(s)/Patent Under Reexamination HOON ET AL.	
	Examiner Sean E. Aeder, Ph.D.	Art Unit 1642	Page 1 of 2

U.S. PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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*	U	Tockman et al (Cancer Res., 1992, 52:2711s-2718s)
*	V	Koyanagi et al (J Clin Oncol, 2005, 23(31):8057-8064)
*	W	Palmieri et al (March 2001, Journal of Clinical Oncology, 19(5):1437-1443)
*	X	Scholl et al (February 2001, Cancer Research, 61:823-826)

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	Examiner Sean E. Aeder, Ph.D.	Art Unit 1642	Page 2 of 2

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